

# LI, Wenzhe

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## Education

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09.2018-present	<b>Ph.D.</b>	<b>Mechanical Eng.</b> , University of Cincinnati, USA. NSF Industry/University Cooperative Research Center (I/UCRC) for Intelligent Maintenance Systems (IMS)
09.2015-03.2018	<b>M.E.</b>	<b>Control Sci. and Eng.</b> , Beihang University, China.
02.2016-07.2016	<b>XCH.</b>	<b>Information Technology</b> , University of Wollongong, Australia.
09.2011-07.2015	<b>B.E.</b>	<b>Quality and Reliability Eng.</b> , Beihang University, China
09.2013-07.2015	<b>B.A.</b>	<b>English Literature</b> , Beihang University, China.

## Research Focus

Prognostics and Health Management, Deep Learning based Fault Detection and RUL Prediction, Digital Twin Technology for Manufacturing Process, Big Data Analysis in Semiconductor Manufacturing

## Professional Skills

Matlab, Python, C, R, Keras, Pytorch, Solidworks, AutoCAD, Altium Designer

## Research Experience

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10.2018-present	<b>Physics Informed Digital Twin for Optical Lens Module Virtual Assembling</b> , Collaborate project with Hon Hai/Foxconn Technology Group. <ul style="list-style-type: none"> <li>Digital Twin assisted Smart Lens Manufacturing.</li> <li>Digital Twin assisted Optical Lens Injection Molding Optimization.</li> </ul>
10.2019- present	<b>Process Control (APC) Techniques and Machine Learning Algorithms in Semiconductor Manufacturing</b> , Collaborate project with Hitachi/ Hitachi High-Technologies Corporation. <ul style="list-style-type: none"> <li>Semiconductor Etching Data Analysis.</li> <li>Developing etching machine chamber matching methodologies to optimize process recipes for correcting the mismatch of the individual chamber.</li> </ul>
10.2018- present	<b>Data Driven Prediction Methodologies for Machine Remaining Useful Life (RUL)</b> , <ul style="list-style-type: none"> <li>Aero-engine RUL/ Wind speed prediction based on deep learning method.</li> <li>Aero-engine RUL/ Wind speed prediction based on Bayesian method.</li> </ul>
10.2018- present	<b>Deep Learning for PHM, FDC and Reliability Analysis</b>

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## Work Experience

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07.2019-11.2019 **Hon Hai/Foxconn Technology Group, L Group**

Internship *Industry Data Scientist*

- Developed Optical Lens Injection Molding Digital Twin Model
- Developed Mold Alignment Failure Analysis and RUL Prediction Methodology & GUI
- Developed Optical Lens Module Virtual Assembling Optimization Methodology

06.2020-08.2020 **Hitachi/ Hitachi High-Technologies Corporation**

Internship *Data Scientist*

- Conduct Semiconductor Etching Process Data Analysis
- Developed Chamber Matching Methodology based on Process Measurement and Wafer Map
- Developed Etching Recipe Optimization Methodology

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## Publications

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- W. Li, X. Jia, X. Li, Y. Wang, J. Lee. A Markov model for short term wind speed prediction by integrating the wind acceleration information. *Renewable Energy* (2020).
- H. Cai, J. Feng, Q. Yang, W. Li, J. Lee. A virtual metrology method with prediction uncertainty based on Gaussian process for chemical mechanical planarization. *Computers in Industry* 119 (2020).
- H. Cai, J. Feng, W. Li, Y. Hsu, J. Lee. Similarity-based Particle Filter for Remaining Useful Life prediction with enhanced performance. *Applied Soft Computing*, 106474 (2020).
- H. Cai, X. Jia, J. Feng, W. Li, Y. Hsu, J. Lee, Gaussian Process Regression for numerical wind speed prediction enhancement, *Renewable Energy*, (2019)
- X. Jia, H. Cai, Y. Hsu, W. Li, J. Feng, J. Lee, A Novel Similarity-based Method for Remaining Useful Life Prediction, (2019)
- Y. Xu, W. Hou, W. Li, N. Zheng, Aero-engine Gas-path Fault Diagnosis based on Spatial Structural Characteristics of QAR Data. *Proceedings of Annual Reliability and Maintainability Symposium*, (2018)
- J. Shi, W. Li, X. Guo, Y. Yang, General models for system reliability and testability optimization considering multi mission profiles, *PHM-Harbin 2017 – Proceedings*, (2017)
- J. Shi, X. Guo, W. Li, A Method of Testability Optimization Based on BIT Working Mode Considering the Basic Reliability, *PHM-Harbin 2017 - Proceedings*, (2017)
- J. Shi, W. Li, X. Guo, A demonstration of build-in test design verification for a typical avionic power circuit using Matlab Stateflow, *Proceedings of 2nd International Conference on Reliability Systems Engineering*, (2017)
- J. Shi, X. Guo, W. Li, An Embedded Diagnosis Semi-physical System of Typical Avionics Based on LabVIEW and MATLAB, *Proceedings of 2nd International Conference on Reliability Systems Engineering*, (2017)
- W. Li, J. Shi, X. Duan, X. Guo, A test point selection method based on recognition of typical topology structure of complex networks, *Proceedings of the 27th European Safety and Reliability Conference*, (2017)
- Y. Zhao, J. Shi, W. Li, W. Cui, Research on false alarm identification method considering BIT test threshold, *Proceedings of the 27th European Safety and Reliability Conference*, (2017)